

<b>Notice of References Cited</b>	Application/Control No. 10/761,080		Applicant(s)/Patent Under Reexamination BEAUCHAMP, PHILLIP J.	
	Examiner Binh X. Tran		Art Unit 1765	Page 1 of 1

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*	A	US-2004/0179193	09-2004	Maezono et al.	356/239.1
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